Characterisation of 1200 V RB-IGBTs with different irradiation levels under hard and soft switching conditions

Blinov, Andrei; Korkh, Oleksandr; Vinnikov, Dmitri; Waind, Peter 2018 20th European Conference on Power Electronics and Applications (EPE'18 ECCE Europe): Riga, Latvia, 17-21 September 2018 2018 / p. 1382-1391: ill

https://ieeexplore.ieee.org/document/8515535

Operation of Single-Chip MOSFET and IGBT Devices after failure due to repetitive avalanche [Electronic resource] Blinov, Andrei; Norrga, Staffan; Tibola, Gabriel EPE'15 ECCE Europe: 8-10 September 2015, Geneva, Switzerland: 17th European Conference on Power Electronics and Applications 2015 / p. 1-9: ill. [USB] https://dx.doi.org/10.1109/EPE.2015.7309190

Reliability analysis of micro-inverters considering PV module variations and degradation rates

Liivik, Elizaveta; Sangwongwanich, Ariya; Blaabjerg, Frede 2018 20th European Conference on Power Electronics and Applications (EPE'18 ECCE Europe): Riga, Latvia, 17-21 September 2018 2018 / p. 1475-1482: ill https://ieeexplore.ieee.org/document/8515325